

**Search Notes**

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Examiner

Anthony Weier

Applicant(s)/Patent under  
Reexamination

SHEN ET AL.

Art Unit

1761

**SEARCHED**

Class	Subclass	Date	Examiner
426	656, 634, 590, 598	1/7/2006	AW

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor Search	1/7/2006	AW